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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/530,815  
Applicant : Moonhor REE et al.  
Filed : April 8, 2005  
TC/A.U. : 2811  
Examiner :

Docket No. : 1751-380  
Customer No. : 06449  
Confirmation No. : 4409

INFORMATION DISCLOSURE STATEMENT

Director of the United States Patent  
and Trademark Office  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application.

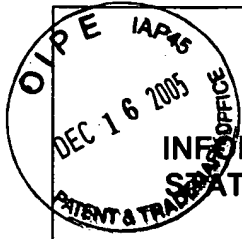
Materials submitted for consideration are listed on the attached form PTO-1449.

Respectfully submitted,

By G. F. Rothwell

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Enclosure(s): (1) cited reference



**INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

				Complete if Known	
				Application Number	10/530,815
				Filing Date	April 8, 2005
				First Named Inventor	Moonhor REE et al.
				Group Art Unit	2811
				Examiner Name	
				Confirmation No.	4409
Sheet	1	of	1	Attorney Docket Number	1751-380

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		
	1	4,652,467		BRINKER et al.	03-24-1987
	2	5,378,790		MICHALCZYK et al.	01-03-1995
	3	6,107,357		HAWKER et al.	08-22-2000
	4	6,495,479	B1	WU et al.	12-17-2002
	5	2001/0055891	A1	KO et al.	12-27-2001

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>
		Office Code <sup>3</sup>	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
	6	KR	10-2005-0000831		POSTECH FOUNDATION	01-06-2005	AB

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code. <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.